

Random Number Generation Using MSP430™ MCUs

MSP430 Applications

ABSTRACT

Many applications require the generation of random numbers. These random numbers are useful for applications such as communication protocols, cryptography, and device individualization.

Generating random numbers often requires the use of expensive dedicated hardware. Using the two independent clocks available on the MSP430F2xx family of devices, software can generate random numbers without such hardware.

Source files for the software described in this application report can be downloaded from <http://www.ti.com/lit/zip/sl原因338>.

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1 Introduction

The very-low-frequency oscillator (VLO) and digitally controlled oscillator (DCO) are two independent clock systems, each having its own timing source. Because the clocks are independent, the time difference between edge transitions of these two clock sources varies. The timing differences between these two clock systems can be exploited to generate a stream of random bits. In one VLO clock cycle, there are always approximately the same number of DCO pulses. However, because the two clock sources vary independently from each other, whether this number of pulses is even or odd is not predictable. More importantly, this number is not predictable even if the previous result is known.

Therefore, Timer_A can be configured to continuously count the number of DCO clock cycles per VLO clock cycle, and the least-significant bits (LSBs) from 16 of these results can be concatenated to form a random 16-bit integer.

2 Setup

Timer_A is configured in capture mode. SMCLK is sourced from the DCO and set as the input clock to Timer_A. ACLK is sourced from the VLO, which is the trigger for the capture. Timer_A counts the number of DCO clock pulses before the next VLO low-to-high transition occurs. The number of DCO clock pulses is saved by the timer in a capture/compare register (CCR). The LSB from the CCR is saved by left shifting it into a CPU register (R12). This process is repeated until 16 LSBs have been saved, forming a 16-bit result that is almost random.

3 Adding Randomness

The example software included also takes several measures that are designed to increase the randomness of the numbers measured and to make the overall system less predictable.

- Each time a CCR LSB is shifted, the BCSCCTL1 register has the number five added to it. This addition changes the RSEL bits, causing the DCO speed to change relative to the VLO through each loop. Although any number could be used, testing showed that five caused a large enough step change to significantly vary the DCO with respect to the VLO.
- Each time a CCR LSB is shifted, the two LSBs from the R12 register are XORed into the DIVA bits of the BCSCCTL1. The DIVA bits control the divider used for the VLO before it reaches the timer. This also changes the relationship between the VLO and DCO as measured by the timer.
- Each result bit is actually the result of a majority vote of five loops. Each loop generates its own LSB from the CCR as described earlier, but the majority vote of five is used to select the final resultant bit. This majority vote system more evenly distributes the results and causes them to pass the poker test for randomness as described in [Section 6](#).

4 Usage

[Section 3](#) describes methods that add randomness, and [Section 6](#) describes how these methods have been tested to more evenly distribute the resultant data. These methods do, however, make changes to the clock system of the MSP430™ MCU, which could interfere with other running processes. Such considerations should be made when designing a system.

If such clock-system changes are not acceptable for a running application, it still may be possible to make use of the methods presented in this application report. Instead of using these methods each time a random number is desired, an initial seed could be generated. This seed value would use these methods, and do so at device startup, before any other processes that rely on the clock system have begun. This seed could be used as a seed for a pseudo-random number generation (PRNG) algorithm such as a steam cipher.[1] This method, although more CPU intensive, could also yield numbers with good random properties, depending on the PRNG used.

5 Overview

[Figure 1](#) shows the flow of the software included with this application report.

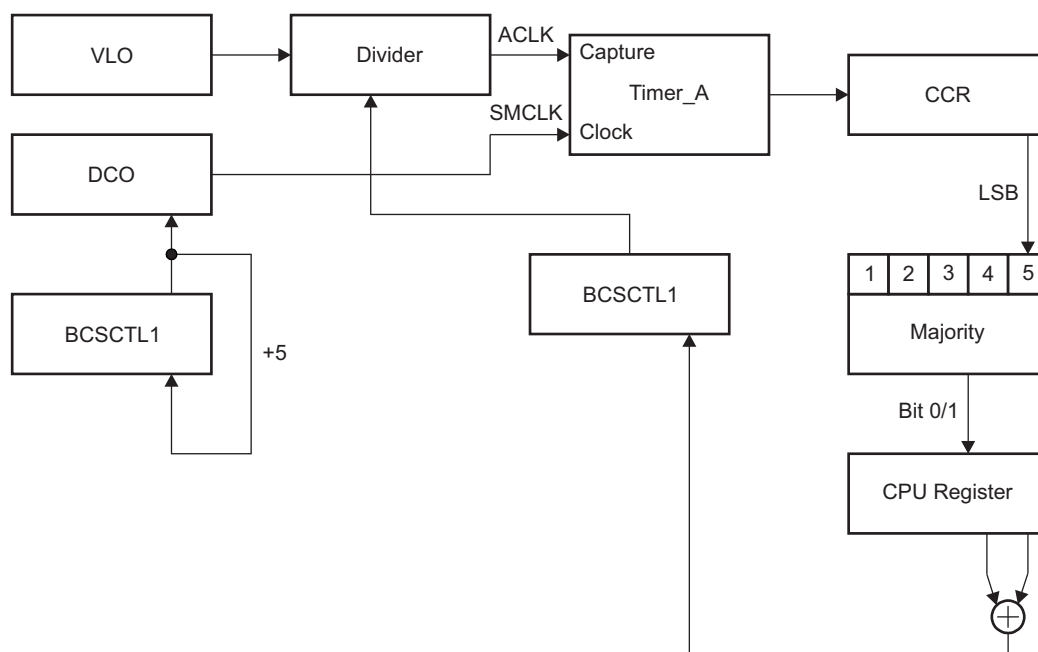


Figure 1. Software Overview Block Diagram

6 Testing for Randomness

The Federal Information Processing Standards (FIPS) describe a series of statistical tests for randomness. Included with the source code for this random number generator is a C file called `fips_test.c`. This source code implements the FIPS 140-2 tests for randomness. The results of these tests are saved in global variables and can be viewed with a debugger to verify the functionality of the random number generator.

Although the tests are included for statistical information, this application report has not undergone official FIPS certification or testing.

The methods described in this application report make use of timing differences between ACLK and SMCLK in the MSP430 MCU. The VLO was chosen for its device-to-device variation and drift with temperature and voltage. This drift only adds to the observed entropy, and sufficiently random numbers are generated under constant temperature and voltage conditions. These factors also add to the randomness that is observed between devices.

The FIPS 140-2 test is only a necessary requirement for the random numbers generated here. For an application that requires cryptographic secure random numbers, it is necessary to create a model of the system and evaluate the entropy that is generated.[2]

The IEEE paper [Analysis of Random Number Generator from Texas Instruments in MSP430x5xx Families](#) provides a more in-depth analysis of the randomness of the generator discussed in this document.

7 LFXT1 and VLO

ACLK could also be sourced from LFXT1 with a 32-kHz crystal. This method can also be used to generate random numbers, but it is less reliable, because of the more predictable nature of the 32-kHz crystal. It is also less secure, because one of the clock sources is now sourced into the microcontroller externally. This fact could be used by an attacker looking to influence the selection of random numbers and compromise a system. These facts should be weighed against the security requirements of a system when deciding to use LFXT1 as the ACLK source for random number generation.

8 References

1. U. Kaiser, [Hermes8: A Low-Complexity Low-Power Stream Cipher](#)
2. W. Schindler, [Evaluation Criteria for True \(Physical\) Random Number Generators Used in Cryptographic Applications](#), CHES2002 workshop
3. [MSP430x2xx Family User's Guide](#)
4. [MSP430x1xx Family User's Guide](#)
5. [FIPS PUB 140-2](#), National Institute of Standards and Technology
6. [Analysis of Random Number Generator from Texas Instruments in MSP430x5xx Families](#)

Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

Changes from October 13, 2006 to May 16, 2018	Page
• Editorial changes throughout document.....	1
• Added link to related IEEE paper as the last paragraph of Section 6 , <i>Testing for Randomness</i>	3

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